



September 2007



## FGPF30N30TD 300V, 30A PDP Trench IGBT

### Features

- High current capability
- Low saturation voltage:  $V_{CE(sat)} = 1.4V$  @  $I_C = 20A$
- High input impedance
- Fast switching
- RoHS compliant

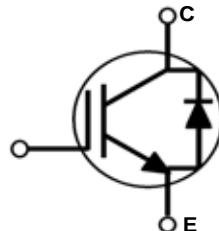
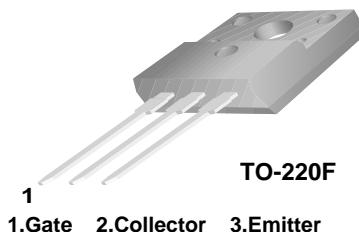
### Applications

- PDP System



### General Description

Using Novel Trench IGBT Technology, Fairchild's new series of trench IGBTs offer the optimum performance for PDP applications where low conduction and switching losses are essential.



### Absolute Maximum Ratings

Symbol	Description	Ratings	Units
$V_{CES}$	Collector to Emitter Voltage	300	V
$V_{GES}$	Gate to Emitter Voltage	$\pm 30$	V
$I_C$ pulse (1)	Pulsed Collector Current @ $T_C = 25^\circ C$	80	A
$I_F$	Diode Continuous Forward Current @ $T_C = 100^\circ C$	10	A
$I_{FM}$	Diode Maximum Forward Current	40	A
$P_D$	Maximum Power Dissipation @ $T_C = 25^\circ C$	44.6	W
	Maximum Power Dissipation @ $T_C = 100^\circ C$	17.8	W
$T_J$	Operating Junction Temperature	-55 to +150	$^\circ C$
$T_{stg}$	Storage Temperature Range	-55 to +150	$^\circ C$
$T_L$	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 seconds	300	$^\circ C$

### Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}(IGBT)$	Thermal Resistance, Junction to Case	-	2.8	$^\circ C/W$
$R_{\theta JC}(DIODE)$	Thermal Resistance, Junction-to-Case for Diode	--	3.0	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	-	62.5	$^\circ C/W$

#### Notes :

(1) Repetitive test, Pulse width = 100usec, Duty = 0.1

\*  $I_C$ \_pulse limited by max  $T_J$

## Package Marking and Ordering Information

Device Marking	Device	Package	Packaging Type	Qty per Tube	Max Qty per Box
FGPF30N30TD	FGPF30N30TDTU	TO-220F	Rail / Tube	50ea	-

## Electrical Characteristics of the IGBT $T_C = 25^\circ\text{C}$ unless otherwise noted

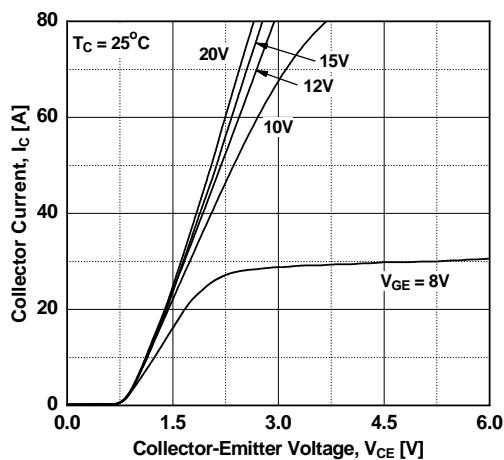
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
<b>Off Characteristics</b>						
$\text{BV}_{\text{CES}}$	Collector to Emitter Breakdown Voltage	$V_{\text{GE}} = 0\text{V}, I_{\text{C}} = 250\mu\text{A}$	300	-	-	V
$\Delta \text{BV}_{\text{CES}}/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	$V_{\text{GE}} = 0\text{V}, I_{\text{C}} = 250\mu\text{A}$	-	0.26	-	$\text{V}/^\circ\text{C}$
$I_{\text{CES}}$	Collector Cut-Off Current	$V_{\text{CE}} = V_{\text{CES}}, V_{\text{GE}} = 0\text{V}$	-	-	100	$\mu\text{A}$
$I_{\text{GES}}$	G-E Leakage Current	$V_{\text{GE}} = V_{\text{GES}}, V_{\text{CE}} = 0\text{V}$	-	-	$\pm 400$	nA
<b>On Characteristics</b>						
$V_{\text{GE}(\text{th})}$	G-E Threshold Voltage	$I_{\text{C}} = 250\mu\text{A}, V_{\text{CE}} = V_{\text{GE}}$	3.0	4.5	5.5	V
$V_{\text{CE}(\text{sat})}$	Collector to Emitter Saturation Voltage	$I_{\text{C}} = 10\text{A}, V_{\text{GE}} = 15\text{V}$	-	1.2	1.5	V
		$I_{\text{C}} = 20\text{A}, V_{\text{GE}} = 15\text{V}$	-	1.4	-	V
		$I_{\text{C}} = 30\text{A}, V_{\text{GE}} = 15\text{V}, T_C = 25^\circ\text{C}$	-	1.7	-	V
		$I_{\text{C}} = 30\text{A}, V_{\text{GE}} = 15\text{V}, T_C = 125^\circ\text{C}$	-	1.6	-	V
<b>Dynamic Characteristics</b>						
$C_{\text{ies}}$	Input Capacitance	$V_{\text{CE}} = 30\text{V}, V_{\text{GE}} = 0\text{V}, f = 1\text{MHz}$	-	1540	--	pF
$C_{\text{oes}}$	Output Capacitance		-	65	--	pF
$C_{\text{res}}$	Reverse Transfer Capacitance		-	55	--	pF
<b>Switching Characteristics</b>						
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{\text{CC}} = 200\text{V}, I_{\text{C}} = 20\text{A}, R_G = 20\Omega, V_{\text{GE}} = 15\text{V}, \text{Inductive Load, } T_C = 25^\circ\text{C}$	-	22	--	ns
$t_r$	Rise Time		-	33	--	ns
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time		-	130	--	ns
$t_f$	Fall Time		-	180	300	ns
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{\text{CC}} = 200\text{V}, I_{\text{C}} = 20\text{A}, R_G = 20\Omega, V_{\text{GE}} = 15\text{V}, \text{Inductive Load, } T_C = 125^\circ\text{C}$	-	21	--	ns
$t_r$	Rise Time		-	34	--	ns
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time		-	140	--	ns
$t_f$	Fall Time		-	260	--	ns
$Q_g$	Total Gate Charge		-	65	--	nC
$Q_{\text{ge}}$	Gate to Emitter Charge	$V_{\text{CE}} = 200\text{V}, I_{\text{C}} = 20\text{A}, V_{\text{GE}} = 15\text{V}$	-	10	--	nC
$Q_{\text{gc}}$	Gate to Collector Charge		-	26	--	nC

**Electrical Characteristics of DIODE**  $T_C = 25^\circ\text{C}$  unless otherwise noted

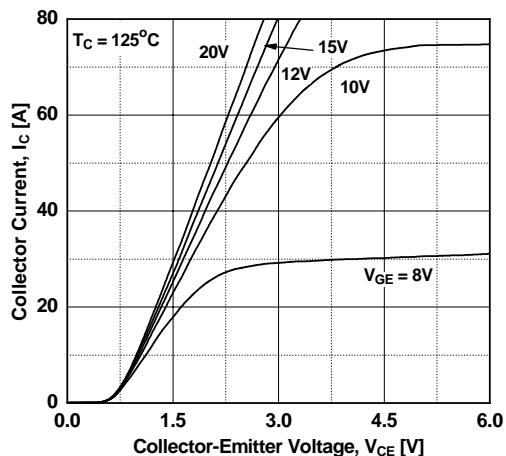
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{FM}$	Diode Forward Voltage	$I_F = 10\text{A}$	$T_C = 25^\circ\text{C}$	--	1.1	1.4
			$T_C = 125^\circ\text{C}$	--	0.9	--
$t_{rr}$	Diode Reverse Recovery Time	$I_F = 10\text{A}$ $dI/dt = 200\text{A}/\mu\text{s}$ Diode Forward Voltage	$T_C = 25^\circ\text{C}$	--	22	--
			$T_C = 125^\circ\text{C}$	--	35	--
$I_{rr}$	Diode Peak Reverse Recovery Current		$T_C = 25^\circ\text{C}$	--	2.7	--
			$T_C = 125^\circ\text{C}$	--	5.6	--
$Q_{rr}$	Diode Reverse Recovery Charge		$T_C = 25^\circ\text{C}$	--	29.7	--
			$T_C = 125^\circ\text{C}$	--	98	--

## Typical Performance Characteristics

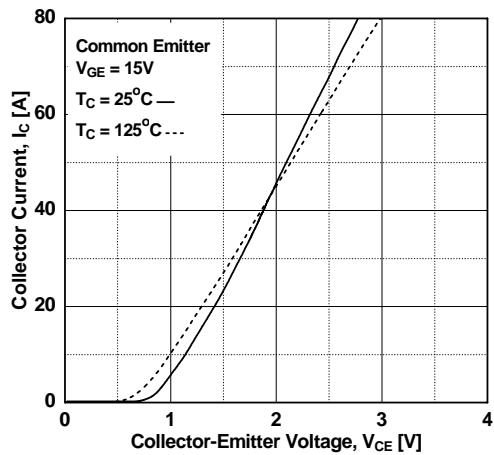
**Figure 1. Typical Output Characteristics**



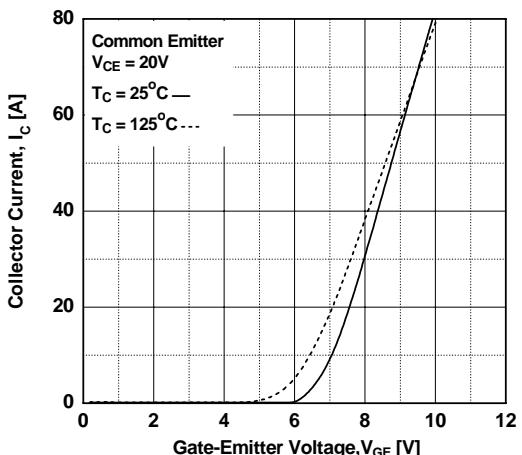
**Figure 2. Typical Saturation Voltage Characteristics**



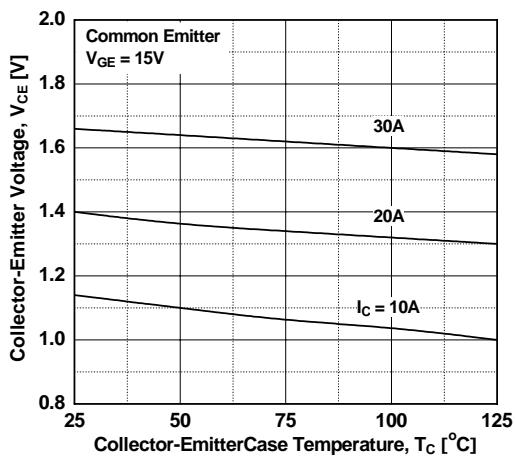
**Figure 3. Typical Saturation Voltage Characteristics**



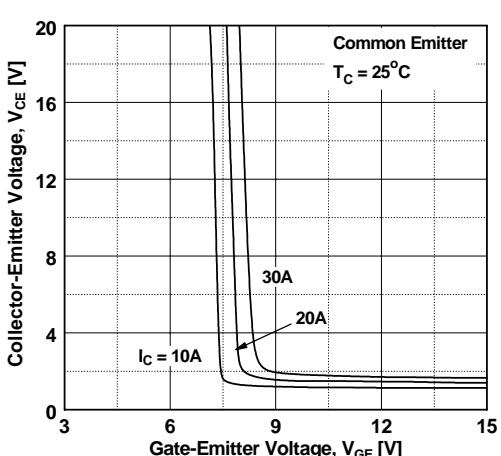
**Figure 4. Transfer Characteristics**



**Figure 5. Saturation Voltage vs. Case**

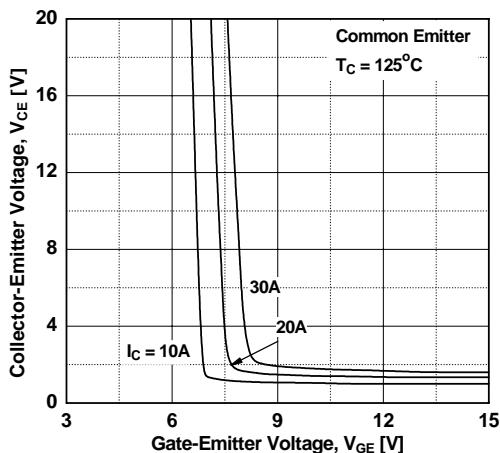


**Figure 6. Saturation Voltage vs. Vge**

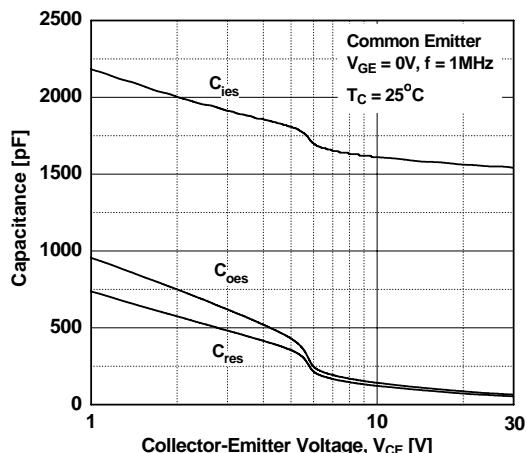


## Typical Performance Characteristics (Continued)

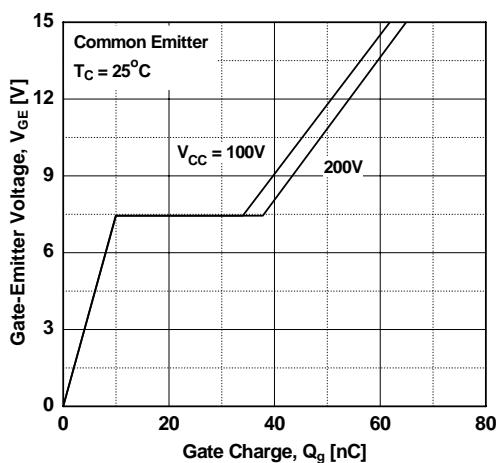
**Figure 7. Saturation Voltage vs. V<sub>GE</sub>**



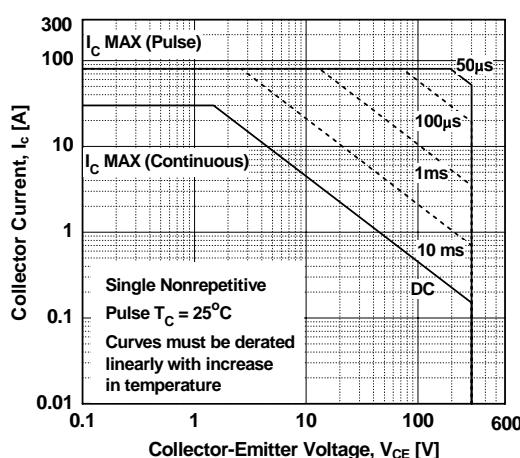
**Figure 8. Capacitance Characteristics**



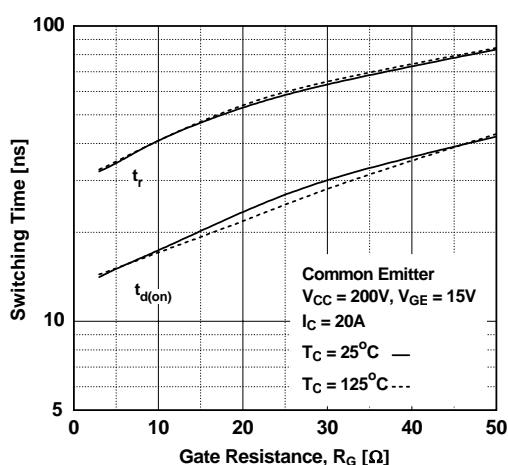
**Figure 9. Gate Charge Characteristics**



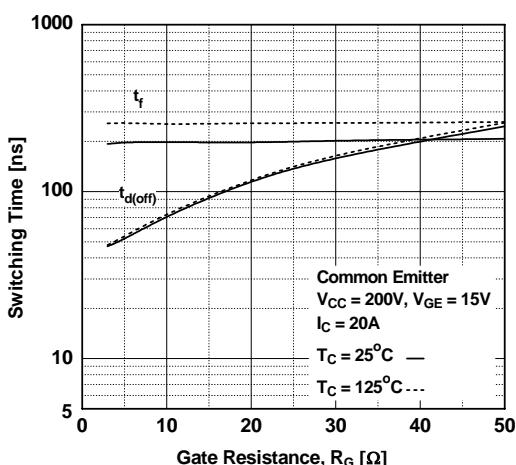
**Figure 10. SOA Characteristics**



**Figure 11. Turn-On Characteristics vs. Gate Resistance**

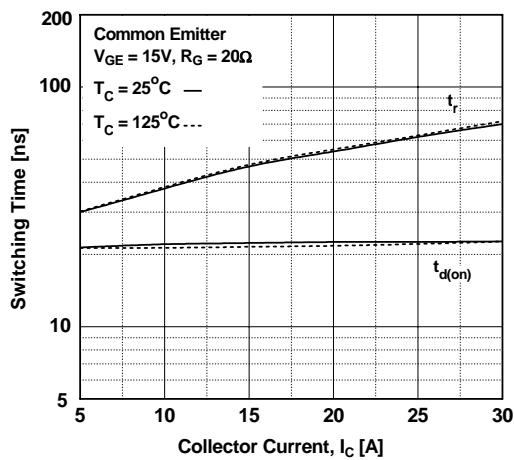


**Figure 12. Turn-Off Characteristics vs. Gate Resistance**

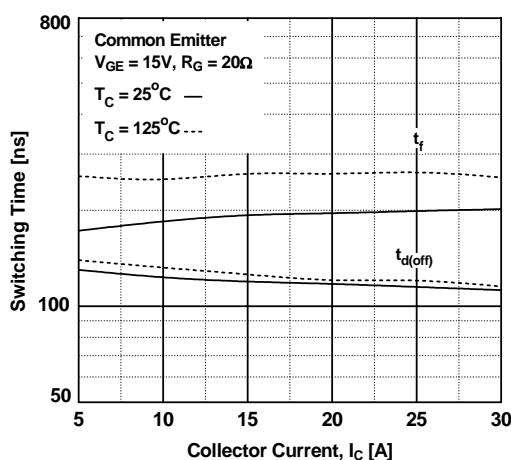


## Typical Performance Characteristics (Continued)

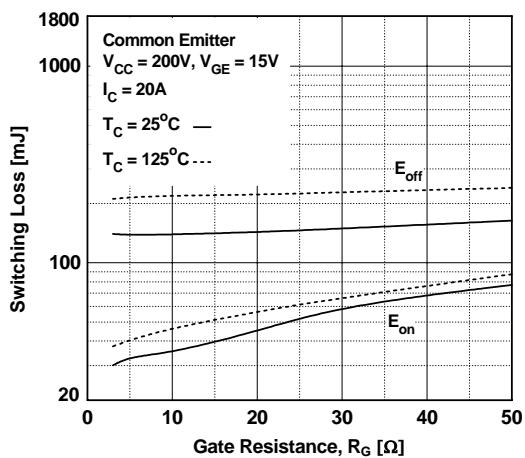
**Figure 13. Turn-On Characteristics vs. Collector Current**



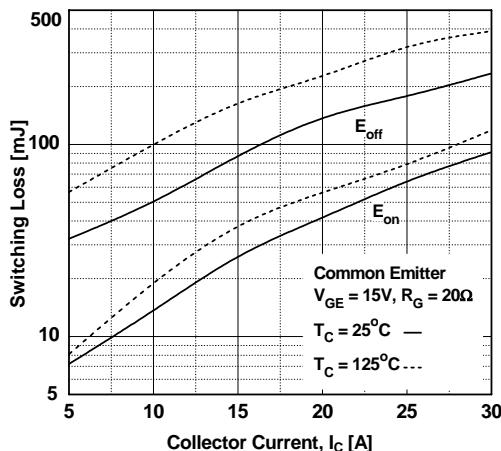
**Figure 14. Turn-Off Characteristics vs. Collector Current**



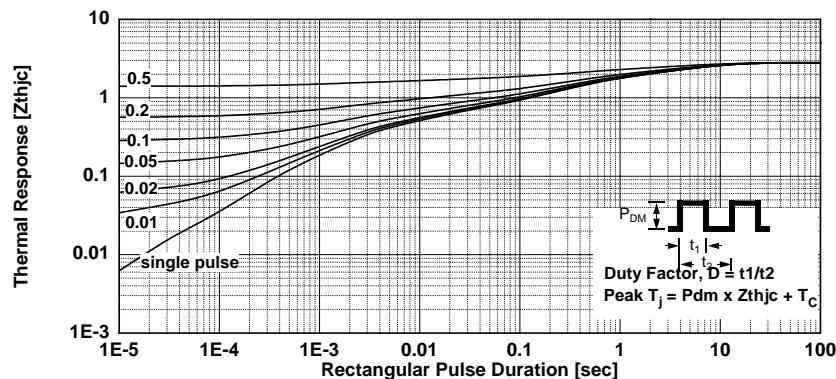
**Figure 15. Switching Loss vs Gate Resistance**



**Figure 16. Switching Loss vs Collector Current**

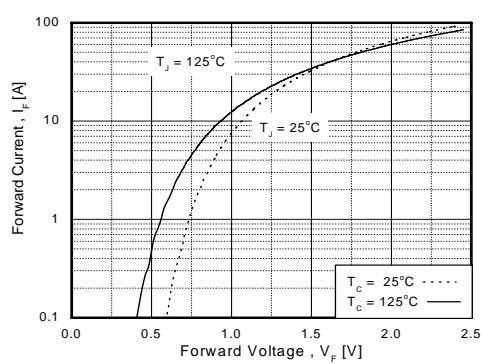


**Figure 17. Transient Thermal Impedance of IGBT**

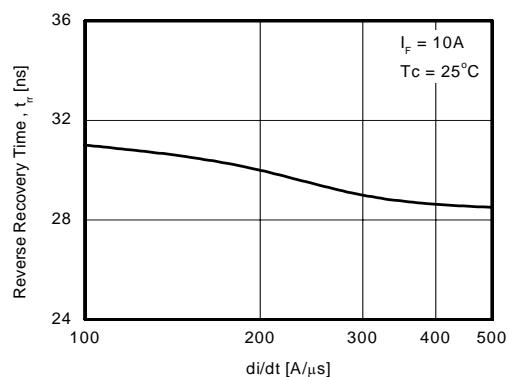


## Typical Performance Characteristics (Continued)

**Figure 18. Forward Characteristics**

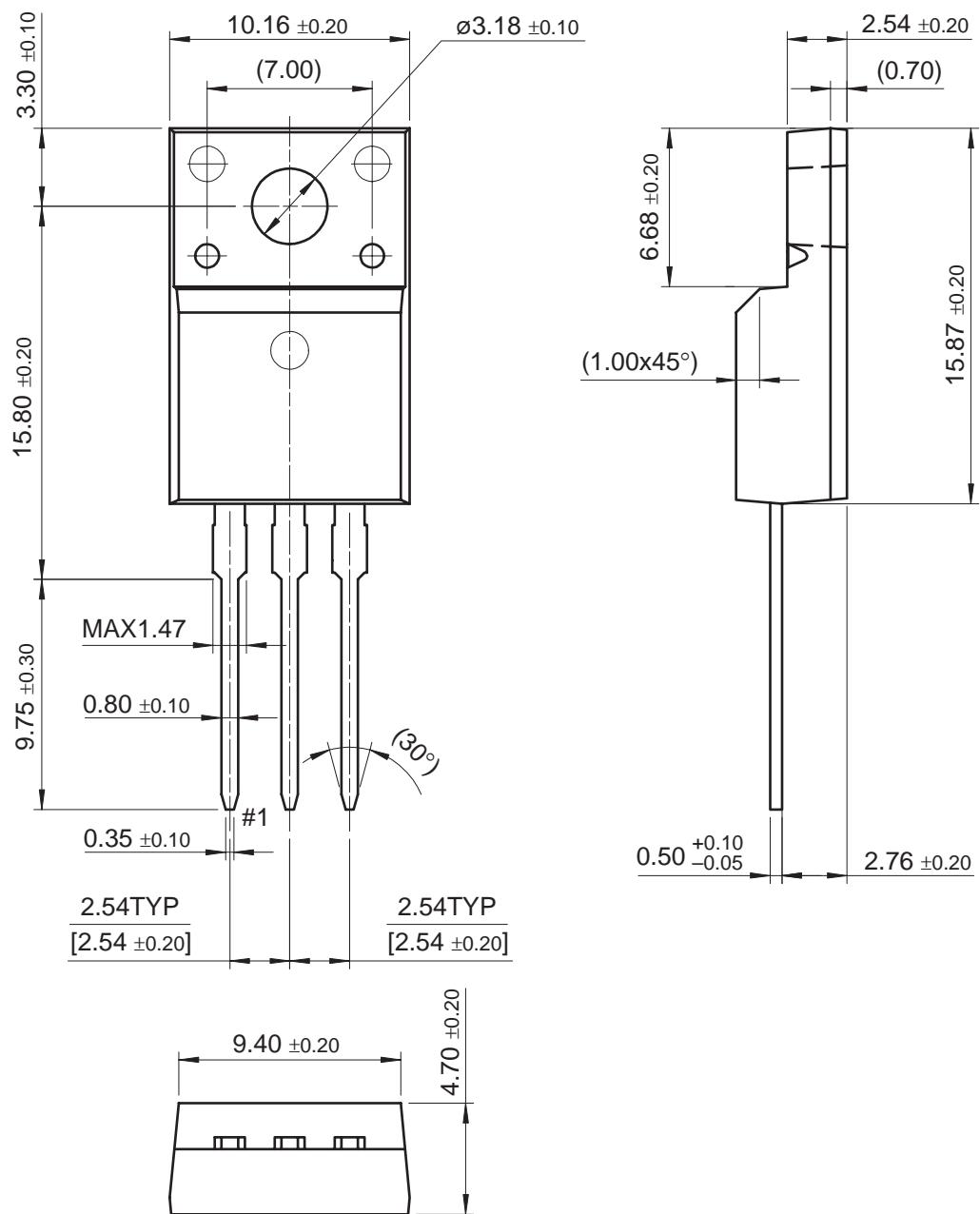


**Figure 19. Typical Reverse Recovery Time**



## Mechanical Dimensions

**TO-220F**



Dimensions in Millimeters



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CTL™	ISOPLANAR™	QFET®	TinyBoost™
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FACT Quiet Series™	MicroFET™	Quiet Series™	TINYOPTO™
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FAST®	Motion-SPM™	SMART START™	TinyPWM™
FastvCore™	OPTOLOGIC®	SPM®	TinyWire™
FP™	OPTOPLANAR®	STEALTH™	μSerDes™
FRFET®	PDP-SPM™	SuperFET™	UHC®
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